3. CIF DATA DEFINITION AND CLASSIFICATION

Example 3.2.3.2. Structure-factor listing.							
loop_							
refln index h							
refln index k							
refln index l							
refln F squared calc							
refln F squared meas							
refln F squared sigma							
refln include status							
	2	0	_0	85.57	58.90	1.45 o	
	3	0	-	15718.18			
		0			49840.09		
	5	0	0	246.85	241.86	10.02 o	
	6	0	0	82.16	69.97	1.93 o	
	7	0	0	1133.62	947.79	11.78 o	
	8	0	0	2558.04	2453.33	20.44 o	
	9	0	0	283.88	393.66	7.79 o	
	10	0	0	283.70	171.98	4.26 o	
I							

the exception of R(I) in Rietveld refinements against powder data, where it is generally called the Bragg R factor, R_{Bragg} or R_B .

The data items in the REFINE_LS_CLASS category are similar to several in the general REFINE category, but correspond to values for separate reflection classes as described in the REFLNS_CLASS category. The data name _refine_ls_class_code identifies the individual classes through a direct match with a corresponding value of _reflns_class_code.

3.2.3.2. Reflection measurements

The categories describing the reflections used in the refinement are as follows:

```
REFLN group
Individual reflections (§3.2.3.2.1)
REFLN
Groups of reflections (§3.2.3.2.2)
REFLNS
REFLNS_CLASS
REFLNS_SCALE
REFLNS SHELL
```

The main category in this group is REFLN, which stores the list of reflections used in the structure refinement process, their associated structure factors and information about how each reflection was handled. The distinction between the REFLN (singular) category and the REFLNS (plural) category parallels the distinction between the categories DIFFRN_REFLN and DIFFRN_REFLNS: data items in the REFLN category store information about individual reflections, while data items in the REFLNS category store information about the complete set of reflections, or about subsets of reflections selected by shells of resolution, scaling factors or other criteria.

3.2.3.2.1. *Individual reflections*

The data items in this category are as follows:

```
REFLN
  _refln_index h
  _refln_index k
 _refln_index_l
  _refln_A_calc
  refln_A_meas
  _refln_B_calc
   refln B meas
  refln_class_code
         reflns class code
   refln_crystal_id
           _exptl_crystal_id
   refln_d_spacing
   refln F calc
   refln F meas
   refln F sigma
   refln F squared calc
  refln F squared meas
```

```
refln F squared sigma
refln include status
refln intensity calc
refln intensity meas
refln intensity sigma
refln_mean_path_length_tbar
refln observed status
refln_phase_calc
refln phase meas
refln refinement status
refln scale group code
         reflns scale group_code
refln sint/lambda
_refln_symmetry_epsilon
refln_symmetry_multiplicity
refln wavelength
refln wavelength id
        diffrn radiation wavelength id
```

The bullet (\bullet) indicates a category key. Where multiple items within a category are marked with a bullet, they must be taken together to form a compound key. The arrow (\rightarrow) is a reference to a parent data item. The dagger (\dagger) indicates a deprecated item, which should not be used in the creation of new CIFs.

Example 3.2.3.2 shows a typical structure-factor listing produced by a refinement program. This kind of structure-factor listing is suitable for deposition with a journal or a database. The Miller indices for each reflection are accompanied by the calculated and measured values of the quantity used in the refinement, and the standard uncertainty derived from the measurement. There is also an indication of whether each reflection was included in the refinement and in the calculation of R factors.

In this example, the squared structure factors $|F|^2$ are listed. When refinement is performed against the structure factors F or the intensities I, the data items $\tt refin_F_calc$ or $\tt refin_intensity_calc}$ and the corresponding data names for the measured values and uncertainties should be used.

Individual calculated structure-factor components $A = |F|\cos\varphi$ and $B = |F|\sin\varphi$ may also be listed, along with the phase φ , using the data names <code>refln_A_calc</code>, <code>refln_B_calc</code> and <code>refln_phase_calc</code>. Corresponding measured values have equivalent *_meas names.

The _refln_include_status flag is used to indicate whether reflections were used in the refinement and in the calculation of R factors, and if they were not used, to give the reason for exclusion of the reflection from the refinement. The flag o, which indicates that a reflection was used in the refinement, was originally chosen to indicate that the value of the reflection was higher than the limit specified by _reflns_observed_criterion and that the reflection was thus 'observed'. The data item _reflns_observed_criterion is now deprecated in favour of _reflns_threshold_status, and the value o is now taken to indicate not only that the reflection has an intensity suitable for inclusion in the refinement, but also that the reflection satisfies all other criteria used to select reflections for inclusion in the refinement.

Various other flags indicate reflections that were not included in the refinement. Reflections outside the range of d spacings bounded by the values <code>refine_ls_d_res_high</code> and <code>refine_ls_d_res_high</code> and <code>refine_ls_d_res_low</code> are flagged with h or l, respectively. Reflections within the resolution limits but below the intensity threshold are flagged with <. Systematically absent reflections are flagged with -. Sometimes a value can be identified as having a systematic error; these reflections can be flagged with x. However, great care must be taken in excluding reflections with apparently 'anomalous' structure factors (*i.e.* where the measured values are substantially different from the calculated ones), so as not to introduce bias into the refinement.

The flag _refln_refinement_status is used specifically to indicate whether a reflection was included in or excluded from

the refinement. Use of <code>_refln_include_status</code> to provide more information about each reflection is greatly preferred.

Other data names in this category allow the recording of specific information about each reflection, such as the symmetry reinforcement factor ε , the number of reflections symmetry-equivalent under the Laue symmetry, the d spacing, the mean path length through the crystal \bar{t} , the $(\sin\theta)/\lambda$ value and, in the case of Laue experiments, the mean wavelength of the radiation. (For polychromatic radiation, the wavelength information might instead be given by <code>refln_wavelength_id</code>, which is a code identifying a matching entry in the DIFFRN RADIATION category.)

Other codes provide links to identifiers in other categories. The <code>_refln_class_code</code> identifies a set of reflections binned as described by entries in the REFLNS_CLASS category. <code>_refln_scale_group_code</code> identifies groups of reflections to which the same structure-factor scaling has been applied.

Note that the values of the Miller indices in this list must correspond to the cell defined by the lengths and angles recorded in the CELL category; they may, however, be different from the Miller indices in the DIFFRN_REFLN list if a transformation of the original cell has taken place. In this case, the transformation matrix is given using the _diffrn_reflns_transf_matrix_* items.

The usual use of a CIF as an archive of a completed structure determination implies that the values given in the REFLN list are derived from the final cycle of refinement, but this is not a formal requirement. Care should be taken when preparing a CIF for archiving that the structural model corresponds to the refinement cycle summarized in the accompanying REFLN table, especially if the file is constructed from fragments output from different programs.

3.2.3.2.2. Groups of reflections

The data items in these categories are as follows:

```
reflns d resolution high
  reflns_d_resolution_low
  reflns Friedel coverage
  reflns limit h max
  reflns limit h min
  reflns limit k max
  reflns limit k min
  reflns limit 1 max
  reflns limit 1 min
  reflns number gt
 reflns number observed
   reflns number total
  reflns observed criterion
  reflns special details
  _reflns_threshold_expression
(b) REFLNS CLASS
 _reflns_class_code
  reflns class d res high
  _reflns_class_d_res_low
  _reflns_class_description
  _reflns_class_number_gt
  reflns_class_number_total
  reflns class R factor all
  reflns_class_R_factor_gt
  reflns class R Fsqd factor
  reflns class R I factor
  _reflns_class_wR_factor_all
(c) REFLNS SCALE
 reflns scale group code
  reflns scale meas F
  refins scale meas F squared
  reflns scale meas intensity
(d) REFLNS SHELL
  reflns shell d res high
  reflns_shell_d_res_low
```

```
reflns shell meanI over sigI all
 reflns_shell_meanI_over_sigI_gt
 reflns shell meanI over sigI obs
  reflns shell meanI over uI all
  reflns shell meanI over uI gt
  reflns_shell_number_measured_all
   reflns_shell_number_measured_gt
 reflns_shell_number_measured_obs
  reflns shell number possible
  reflns shell number unique all
  reflns shell number unique gt
 reflns shell number unique obs
  reflns_shell_percent_possible_all
  reflns_shell_percent_possible_gt
† _reflns_shell_percent_possible_obs
  reflns shell Rmerge F all
  reflns shell Rmerge F gt
 reflns shell Rmerge F obs
  reflns shell Rmerge I all
  reflns shell Rmerge I gt
  reflns shell Rmerge I obs
```

The bullet (\bullet) indicates a category key. Where multiple items within a category are marked with a bullet, they must be taken together to form a compound key. The dagger (\dagger) indicates a deprecated item, which should not be used in the creation of new CIFs.

The data items in the REFLNS category describe properties or attributes of the complete set of reflections used in the structure refinement. Several are derivative and may be obtained from the information in the reflections list, but it is convenient to present them separately so that they do not need to be calculated again. They can also be used to check the consistency of the reflections list.

The _reflns_limit_* data items define the upper and lower bounds on the Miller indices and on the interplanar *d* spacings.

The _reflns_threshold_expression is a text field describing the criterion applied to mark individual reflections as 'significantly intense' (*i.e.* distinct from the background level). This is typically expressed as a multiple of the standard uncertainty on the quantity used in refinement, e.g. I>2u(I).

The number of reflections with values higher than the threshold is reported in <code>reflns_number_gt</code>. The total number of reflections measured is given by <code>reflns_number_total</code>. Although the use of these data names appears to be obvious, different practices have been used in the past to report total numbers (e.g. by neglecting symmetry-equivalent reflections) and the definitions in the dictionary should be consulted. Both numbers may contain Friedel-equivalent reflections (those which are symmetry-equivalent under the Laue symmetry but inequivalent under the crystal class).

The proportion of Friedel-related reflections present is reported separately by $_{\tt reflns_Friedel_coverage}$, defined as $(N_C - N_L)/N_L$, where N_C is the number of reflections obtained on averaging under the symmetry of the crystal class and N_L is the number obtained on averaging under the Laue class. The definition in the dictionary provides examples of how the value of this data name may be used as an indicator of the fraction of the available reciprocal space sampled in the diffraction experiment.

The deprecated data names <code>reflns_observed_criterion</code> and <code>reflns_number_observed</code> reflect the old use of 'observed' as a term describing significantly intense reflections. They should not be used in the creation of new CIFs, but are retained to ensure that the information can be extracted from old CIFs.

The free-text field <code>_reflns_special_details</code> can be used to discuss any aspects of the reflections list not covered by other data names. It is recommended that information about the averaging of symmetry-equivalent reflections (including Friedel pairs) should be given here.

The REFLNS_CLASS category is used to summarize the properties of subsets of the reflection list. The data names are analogous to several in the REFLNS and REFINE categories, but are applied to individual classes of reflections labelled by _reflns_class_code and described by _reflns_class_description (see Example 3.2.3.3).

Individual reflections in the structure-factor listing can be recognized through the matching value of <code>_refln_class_code</code> as belonging to a particular class labelled by <code>_reflns_class_code</code>.

Although classes can be assigned according to arbitrary criteria, the specific case for which the REFLNS_CLASS category was designed was the partitioning of the reflection list into contributions from different components in incommensurately modulated structures. However, the formalism is general and other binning strategies can be described. Note, however, that the specific case of processing of reflections by shells of resolution (in macromolecular crystallography, for example) is handled explicitly by the REFLNS SHELL category.

The category REFLNS_SCALE provides a listing of the scale factors applied to individual reflections sharing a common value of _refln_scale_group_code. Each value is indexed by the matching identifier reflns scale group code of this category.

The REFLNS_SHELL category describes the properties of separate resolution shells of reflections and is a special case of the binning of reflections into classes (compare REFLNS CLASS above).

Each shell is defined by an upper and lower resolution limit (_reflns_shell_d_res_high and *_low), and for each shell there are data names for the number of reflections measured and exceeding a threshold of significance, for the percentage of geometrically possible reflections collected, and for the ratios of the mean intensities to their standard uncertainties.

 R_{merge} values are also defined for each shell of resolution (both for all measured reflections and for significantly intense ones).

This category also contains a number of deprecated data names reflecting older terminology and notation. Such data names should not be used in creating new CIFs, but will need to be recognized by CIF-reading software in order to process old CIFs.

3.2.4. Atomicity, chemistry and structure

The core CIF dictionary provides many data names for describing the structural model.

The categories describing the atom sites handle these in a general way as sites of significant electron density which might be contributed to by more than one element species. The chemical identification of the compound under study, and where appropriate a model of the molecular connectivity and bonding, are handled separately by the chemistry-related categories. The geometry-related categories are purely derivative, given knowledge of the positions of the atom sites and the crystallographic symmetry; but as with other examples of derived data, they are given their own data names to provide convenient listings and to check the consistency of information provided by other categories. The symmetry-related data names in the core dictionary are restricted to those essential for the construction of a geometric model; Chapter 3.8

describes a symmetry extension dictionary suitable for a more complete description of crystal symmetry.

3.2.4.1. Atom sites

```
The categories describing atom sites are as follows: ATOM group

Individual atom sites (§3.2.4.1.1)

ATOM_SITE

Collections of atom sites (§3.2.4.1.2)

ATOM_SITES

Atom types (§3.2.4.1.3)

ATOM_TYPE
```

These categories permit the traditional interpretation of regular concentrations of electron density in a crystalline lattice as atom sites containing one or more chemical elements, with complete or partial occupancy, and with a spatial distribution affected by thermal displacement or disorder.

Lists of atom-site coordinates and anisotropic displacement factors are covered by data items in the ATOM_SITE category. Identification of the chemical species occupying each site is handled by data items in the ATOM_TYPE category and data items in the ATOM_SITES category record collective information common to all sites.

While the ATOM_SITE category formally contains the data items describing both positions and atomic displacements, the anisotropic displacement parameters are often given in a separate looped list. In the version of the core dictionary embedded in the macromolecular CIF dictionary, which uses the DDL2 formalism, this is recognized by the creation of a separate, but overlapping, ATOM SITE ANISOTROP category.

3.2.4.1.1. Individual atom sites

The data items in this category are as follows:

```
ATOM SITE
 _atom_site_label
  _atom_site_adp_type
  atom_site_aniso_B_11
  atom site aniso B 12
  atom site aniso B 13
  atom site aniso B 22
  atom site aniso B 23
  _atom_site aniso B 33
  _atom_site_aniso_label
           atom_site_label
  atom_site_aniso_ratio
  atom site aniso type symbol
          atom site type symbol
  atom site aniso U 11
  atom site aniso U 12
  atom site aniso U 13
  {\tt _atom\_site\_aniso\_U\_22}
  atom site aniso U 23
  atom site aniso U 33
  atom site attached hydrogens
  atom site B equiv geom mean
  _atom_site_B_iso_or equiv
  atom site calc attached atom
  atom site calc flag
  _atom_site_Cartn_x
  atom_site_Cartn_y
  atom site Cartn z
  atom_site_chemical_conn_number
           chemical conn atom number
  atom site constraints
 _atom_site_description
  _atom_site_disorder_assembly
  atom_site_disorder_group
  atom site fract x
  _atom_site_fract_y
  atom site fract z
  atom site label component 0
  atom site label component 1
```

102 references